

## **List of invited lectures delivered at conferences**

1. A. Jablonski, „The Role of the Backscattering Factor in Quantitative Auger Electron Spectroscopy”, 2nd Symposium Oberflächen- und Elektronenphysik, Gaussig, Germany, 8 - 11 April, 1980.
2. A. Jablonski, „Auger Electron Spectroscopy. Quantitative Analysis”, Autumn School on Fundamentals and Applications of Surface Analysis, Halle, Germany, 26 October - 1 November, 1980.
3. A. Jablonski, „Elastic Backscattering of Electrons from Surfaces”, 5th Symposium Oberflächen und Elektronenphysik, Gaussig, Germany, 4 - 8 March, 1985.
4. A. Jablonski, „Analiza ilościowa powierzchni ciał stałych za pomocą spektroskopii elektronów Augera”, Ogólnopolskie Doroczne Seminarium Instytutu Technologii Elektronowej Politechniki Warszawskiej n. t. Zastosowania spektroskopii elektronów Augera w technologii materiałów, Warsaw, Poland, 26 - 27 September, 1985.
5. A. Jablonski, „Aspekty ilościowe spektroskopii elektronowych”, Konferencja p.t. Nowoczesne Fizykalne Metody Mikroanalizy, Rudy Raciborskie, Poland, 13 - 17 October, 1986.
6. A. Jablonski, „Elastic Electron Backscattering from Surfaces”, 12th International Seminar on Surface Physics, Piechowice, Poland, 9 – 14 May, 1988.
7. A. Jablonski, „Electron Transport in the Surface Region of Solids”, 7th Seminar of Socialist Countries on Electron Spectroscopy, Bourgas, Bulgaria, 20 - 24 September, 1988.
8. A. Jablonski, „Elastic Scattering and Quantification in AES and XPS”, 5th International Conference on Quantitative Surface Analysis, London, Great Britain, 15 - 18 November, 1988.

9. A. Jablonski, „Zastosowanie spektroskopii elektronów Augera i nadfioletowej spektroskopii fotoelektronów (UPS) do badania powierzchni ciała stałego”, 22 Ogólnopolskie Kolokwium Katalityczne, Cracow, Poland, 6 - 8 February, 1989.
10. A. Jablonski, „Elastic Scattering Effects in Quantitative Surface Analysis by Electron Spectroscopies”, 13th International Seminar on Surface Physics, Piechowice, Poland, 22 - 27 May, 1989.
11. A. Jablonski, „Quantitative Auger Electron Spectroscopy (AES) of Alloys and Compounds”, 42nd Annual Meeting of the Scandinavian Society for Electron Microscopy (SCANDEM-90), Turku, Finland, 10 - 13 June, 1990.
12. A. Jablonski, „Quantitative Analysis of Solid Surfaces by Auger Electron Spectroscopy. Problems and Prospects”, 8th International Seminar on Electron Spectroscopy, Zakopane, Poland, 14 - 18 September, 1990.
13. A. Jablonski, „Studies of Solid State Surface by Electron Spectroscopies. The Effect of Electron Transport.”, Symposium on Physics of Metals, Jaszowiec, Poland, 3 - 7 June, 1991.
14. A. Jablonski, „Elastic Scattering Effects in Surface Sensitive Electron Spectroscopies”, 38th Annual Symposium of the American Vacuum Society, Seattle, USA, 11 - 15 November 1991.
15. A. Jablonski, „Current Problems in Quantitative X-ray Photoelectron Spectroscopy”, Annual Conference on Microbeam Analysis, Nagahama, Japan, 12 - 13 May 1992.
16. A. Jablonski, „Elastic Electron Backscattering from Surfaces. Possible Analytical Applications”, Annual Meeting of Japanese VAMAS. Section of Surface Chemical Analysis, Hamamatsu, Japan, 24 - 25 September, 1992.
17. A. Jablonski, „Electron Transport in Solids. Impact on Applications of Electron Spectroscopies”, 6th Symposium on Surface Physics, Chlum Castle, Czech Republic, 24 -28 May, 1993.

18. A. Jablonski, „Analiza ilościowa AES i XPS. Standardyzacja transportu elektronów”, Seminarium n/t Powierzchni i Struktur Cienkowarstwowych, Raba Nizna, Poland, 3 - 6 November, 1993.
19. A. Jablonski, „Angular Distribution of Photoemission from Amorphous and Polycrystalline Solids”, 2nd International School and Symposium on Synchrotron Radiation in Natural Science, Jaszowiec, Polska, 18 – 26 May 1994.
20. A. Jablonski, „Special Methods of Quantitative XPS Analysis”, 17th International Seminar on Surface Physics, Kudowa, Polska, 6 - 11 June 1994.
21. A. Jablonski, „Rozkład kątowy fotoemisji z powierzchni ciał stałych”, II Seminarium n/t Powierzchni i Struktur Cienkowarstwowych, Kazimierz Dolny, Poland, 14 - 17 September 1994.
22. A. Jablonski, „Recent Developments in Quantitative XPS Analysis”, International Symposium on Present Status and Problems in Surface Analysis by Electron Spectroscopy, Tokio, Japan, 7 - 8 March 1995.
23. A. Jablonski, „Elastic Scattering of Auger Electrons”, IUVSTA Workshop on Auger Electron Spectroscopy: From Physics to Data, Saint-Pierre-de-Chartreuse, France, 1 - 5 May 1995.
24. A. Jablonski, „Distribution of Inner-shell Ionization”, IUVSTA Workshop on Auger Electron Spectroscopy: From Physics to Data, Saint-Pierre-de-Chartreuse, France, 1 - 5 May 1995.
25. A. Jablonski, „Role of Electron-Elastic-Scattering Cross Sections in Surface Sensitive Electron Spectroscopies”, International Symposium on Surfaces and Thin Films of Electronic Materials, Hamamatsu, Japan, 3 - 4 October, 1995.
26. A. Jablonski, „Monte Carlo Simulations of Electron Transport in Quantitative AES and XPS”, 7th Joint Vacuum Conference of Hungary, Austria, Croatia and Slovenia, Debrecen, Hungary, 26 - 29 May 1997.
27. A. Jablonski, „Role of the Electron Transport in Quantitative AES and XPS”, 7th European Conference on Applications of Surface and Interface Analysis (ECASIA 97), Goeteborg, Sweden, 16 - 20 June 1997.

28. A. Jablonski, „Spektroskopie elektronowe AES i XPS: Od fizyki do danych”, 5 Seminarium n/t Powierzchni i Struktur Cienkowarstwowych, Ustroń, Polska, 23 - 26 September 1997.
29. A. Jablonski, „Średnia droga swobodna elektronów w ciałach stałych. Definicja, metodyka wyznaczania oraz bazy danych”, Kongres Polskiego Towarzystwa Próżniowego, Cracow, 25 - 27 May 1998.
30. A. Jablonski, „Elastic Scattering of Photoelectrons”, International Workshop: XPS- From Physics to Data”, Hortobagy, Hungary, 26 – 30 April 1999.
31. A. Jablonski, „Quantitative Analysis of Thin Film Surfaces by Photoelectron and Auger Electron Spectroscopies”, International Summer School on New Trends in Surface and Thin Film Physics and Engineering, Tri Studne, Czech Republic, 14 - 18 June 1999.
32. A. Jablonski, „Monte Carlo Algorithms for EPES Calculations: Stability, Energy Range, and Range of Experimental Configurations”, International Workshop on Inelastic Mean Free Path of Electrons”, Budapest, Hungary, 27 – 29 January 2000.
33. A. Jablonski, “Role of Electron Transport in Surface Analysis by Electron Spectroscopies”, Symposium on Transport Processes in Applied Physics and Risk Analysis, Brussels, Belgium, 12 May 2000.
34. A. Jablonski, „Current Status of Surface Analysis by Electron Spectroscopies: XPS and AES”, 4th Regional Workshop of European Microbeam Analysis Society, Trest, Czech Republic, 17 - 20 May 2000.
35. A. Jablonski, „Improved Correction Methods for Elastic-Scattering Effects in AES and XPS”, International Symposium on Practical Surface Analysis (PSA-01), Nara, Japan, 19 - 21 September 2001.
36. A. Jablonski, „Calculations of the Inelastic Mean Free Path of Electrons from Elastic Peak Intensity – New Developments”, International Workshop on the Inelastic Mean Free Path (IMFP 2002), Prague, Czech Republic, 4 –5 June 2002.

37. A. Jablonski, „Quantification of Surface Analysis by Electron Spectroscopies”, Michal Smialowski International Symposium on Corrosion and Hydrogen Degradation”, Zakopane, Poland, 9 – 13 September 2003.
38. **A. Jablonski**, C. J. Powell, „The Backscattering Factor in AES: New Approach for an old Subject”, 9th International Symposium on Advanced Physical Fields, Tsukuba, Japan, 1 - 4 March 2004.  
(lecture delivered by A. Jablonski).
39. **A. Jablonski**, C. J. Powell, „Monte Carlo Simulation of Electron Transport in Solids: Applications to Electron Backscattering from Surfaces”, 12 International Conference on Solid Films and Surfaces, Hamamatsu, Japan, 21 - 25 June 2004.  
(lecture delivered by A. Jablonski).
40. A. Jablonski, “Comparison of Differential Cross Sections for Elastic Scattering of Electrons: Calculations and Measurements”, IUVSTA Workshop on Electron Scattering in Solids: From Fundamental Concepts to Practical Applications, Debrecen, Hungary, 4 - 8 July 2004.
41. A. Jablonski, „Monte Carlo Simulation of Elastic and Inelastic Backscattering of Electrons from Surfaces”, Workshop on Modeling Electron Transport for Applications in Electron and X-ray Analysis and Metrology, Gaithersburg, Maryland, USA, 8 – 10 November 2004.
42. A. Jablonski, „Elastic and Inelastic Elektron Backscattering from Surfaces”, 10th Symposium on Surface Physics, Prague, Czech Republic, 10 – 15 July 2005.
43. A. Jablonski, „Modeling of Elastic and Inelastic Electron Collisions in a Solid”, Workshop on Modeling and Standardization of Surface Analysis, Brussels, Belgium, 13 – 15 September 2006.
44. A. Jablonski, „Analiza powierzchni ciał stałych: stan obecny i perspektywy”, I Krajowa Konferencja Nanotechnologii, Wrocław, Poland, 26 – 28 April 2007.
45. A. Jablonski, “Disentangling Intricacies of Electron Transport in Solids”, 5th Conference on Practical Surface Analysis, Kanazawa, Japan, 25 – 28 November 2007.

46. A. Jablonski, „Are Electron Spectroscopies useful in the „Nano” Era?”, Professor Stefan Mróz Symposium, Wroclaw, Poland, 16 - 17 May 2008.
47. A. Jablonski, “The Backscattering Factor in AES. Revival or a New Challenge?” 55th IUVESTA Workshop on Electron Transport Parameters Applied in Surface Analysis, Siofok, Hungary, 14 – 17 September 2008.
48. A. Jablonski, „The Backscattering Factor for Systems with Non-uniform In-depth Profile”, International Workshop for Surface Analysis and Standardization (iSAS-09), Okinawa, Japan, 15 – 18 March 2009.
49. A. Jablonski, “The Backscattering Correction Factor Revisited”, 5th International Symposium on Practical Surface Analysis, Gyeongju, Korea 3 – 7 October, 2010.
50. A. Jablonski, „Role of parameters defining electron transport in quantification of electron spectroscopies”, International Workshop for Surface Analysis and Standardization (iSAS-09), Okinawa, Japonia, 15 - 19 January 2013.
51. A. Jablonski, “Quantification of XPS Analysis of Stratified Samples”, IUVESTA Workshop on Nanostructure Characterization by Electron Beam Techniques (IUVESTA 71), Castle Hernstein, Austria, 24 -28 June, 2013.
52. A. Jablonski, “Quantification of Photoemission by Laboratory Hard X-ray Radiation Sources”, International Workshop on Photon and Fast Ion Induced Processes in Atoms, Molecules and Nanostructures (PIPAMON), Debrecen, Hungary, 24 - 26 March, 2015.
53. A. Jablonski, “Modeling of electron transport in a surface region of solids: Metrology of quantitative analysis by electron spectroscopies”, 7th International Symposium on Practical Surface Analysis (PSA-16), Daejeon, Korea, 16 - 21 October 2016.
54. A. Jablonski, “Parameterization of quantitative applications of electron spectroscopies”, 11th International Symposium on Atomic Level Characterizations for New Materials and Devices (ALC-17), Kauai, USA, Hawaii, 3 - 8 December 2017.